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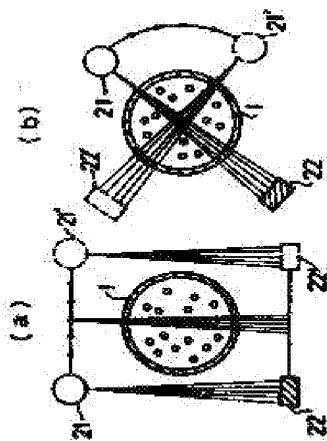
(22)Date of filing : **07.07.1983** (72)Inventor : **MOROOKA SHINICHI**

(54) **METHOD FOR MEASURING LOCAL VOID RATIO DISTRIBUTION**

(57)Abstract:

PURPOSE: To make it possible to measure the local void ratio distribution of a flowing fluid, of which the density is timewise varied, with high accuracy, by continuously performing X-ray or γ -ray computer tomography predetermined times from the outside of a flowline.

CONSTITUTION: X-ray or γ -ray computer tomography apparatuses 21, 22 (the apparatus 21 is an X-ray or γ -ray tube and the apparatus 22 is a detector) are continuously scanned predetermined times from the outside of a flowline through which a fluid to be measured flows. Projection data obtained by scannings are averaged to calculate the local void ratio of the fluid to be measured. Therefore, the void ratio of an entire cross-sectional area can be measured with good accuracy without disturbing the internal flowing in the flowline.



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